

S&H Form: (01/03)

## **REPLY/AMENDMENT FEE TRANSMITTAL**

Attorney Docket No. 1344.1046 Application Number 09/697,179 October 27, 2000 Filing Date Nobuaki MITAMURA et al.

1 1-1-		First Named Inventor		Not	Nobuaki MITAMURA et al.				
				Group A	rt Unit	288	32		
AMOUNT ENCLOSED			110.00	Examiner Name		Krystyna Suchecki			
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	The Commissioner is also authorized to credit any overpayments or charge any additional fees required under 37 CFR 1.16 (filing fees) or 37 CFR 1.17 (processing fees) during the prosecution of this application,								
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Docket No.: 1344,1046

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE # 1B Aurot : ex+(1) M. Brauman 5/21/03

Group Art Unit: 2882

Examiner: Krystyna Suchecki

In re the Application of:

Nobuaki MITAMURA et al.

Serial No. 09/697,179

Confirmation No. 4454

Filed: October 27, 2000

For: AIRGAP TYPE ETALON APPARATUS UTILIZING THE SAME

Commissioner for Patents PO Box 1450 Alexandria, VA 22313-1450

Sir:

AIRGAP TYPE ETALON APPARATUS UTILIZING THE SAME

AMENDMENT

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This is in response to the Office Action mailed January 16, 2003, and having a period for response set to expire on April 16, 2003. A Petition for a one-month extension of time, together with the requisite fee for same, is submitted herewith, thereby extending the period for response to May 16, 2003. The following amendments and remarks are respectfully submitted.

## IN THE SPECIFICATION:

Please AMEND the paragraph beginning at page 4, line 35 to page 5, line 10, as follows:

Meanwhile, the etalon described and established in Japanese Unexamined Patent Publication No. 7-27943 has a constitution in which a solid type etalon and an airgap type etalon are combined with each other. If the temperature rises, the optical thickness (coherence length) of the solid type etalon is increased due to the thermal expansion and the increase of refractive index thereof while the optical thickness of the airgap type etalon is decreased so as to offset such an increased optical thickness, to thereby eventually maintain the total optical thickness of the etalon to be constant. Even in such a constitution, however, it is difficult to realize an etalon having a higher wavelength-temperature characteristic, and there is such a defect that the degree of design freedom of the wavelength-temperature characteristic is restricted as

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